



Variable Pressure Scanning Electron Microscope

Solicitation Number: N00173-08-R-GA01

Agency: Department of the Navy

Office: Office of Naval Research

Location: Naval Research Laboratory

Notice Type:

Modification/Amendment

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July 15, 2008

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July 24, 2008

Response Date:

Jul 30, 2008 4:00 pm

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Classification Code:

66 -- Instruments & laboratory equipment

NAICS Code:

334 -- Computer and Electronic Product Manufacturing/334516 -- Analytical Laboratory Instrument Manufacturing

Synopsis:

Added: Jul 24, 2008 12:45 pm

The purpose of this second amendment is to answer questions for potential offerors.

Q1: Clarification on Section 6. Trade-In of Existing Microscope (OPTIONAL).

A1: The government is requesting one quotation, either with a trade-in and any discount associated with the trade-in OR without trade-in pricing.

Q2: Does the trade-in LEO 1550 SEM have a Beam Blanker?

A2: The system has a beam blanking feature, whereby beam blanking is accomplished by switching to an aperture that does not allow the beam through. There is no built-in automatic beam blanking.

Contracting Office Address:

4555 Overlook Ave. S.W.

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Place of Performance:

At Contractor's facility

United States

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Opportunity History

■ Original Synopsis

Combined Synopsis/Solicitation

Jul 15, 2008

7:00 pm

■ Changed

Jul 21, 2008

12:05 pm

■ **Changed**

Jul 24, 2008

12:45 pm